International Rectifier

IRLR7843PbF IRLU7843PbF

HEXFET® Power MOSFET

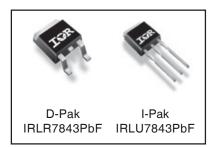
V_{DSS}	R _{DS(on)} max	Qg
30V	3.3 m Ω	34nC

Applications

- High Frequency Synchronous Buck Converters for Computer Processor Power
- High Frequency Isolated DC-DC Converters with Synchronous Rectification for Telecom and Industrial Use
- Lead-Free

Benefits

- Very Low RDS(on) at 4.5V V_{GS}
- Ultra-Low Gate Impedance
- Fully Characterized Avalanche Voltage and Current



Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	30	V
V _{GS}	Gate-to-Source Voltage	± 20	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	161⊕	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	113 ^④	А
I _{DM}	Pulsed Drain Current ①	620	7
P _D @T _C = 25°C	Maximum Power Dissipation ^⑤	140	W
P _D @T _C = 100°C	Maximum Power Dissipation ®	71	7
	Linear Derating Factor	0.95	W/°C
T _J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.05	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ^(S)		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

Notes ① through ⑤ are on page 11

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Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	30			٧	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		19		mV/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		2.6	3.3	mΩ	V _{GS} = 10V, I _D = 15A ③
			3.2	4.0		V _{GS} = 4.5V, I _D = 12A ③
V _{GS(th)}	Gate Threshold Voltage	1.4		2.3	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient		-5.4		mV/°C	
I _{DSS}	Drain-to-Source Leakage Current		l —	1.0	μΑ	$V_{DS} = 24V, V_{GS} = 0V$
				150		$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
gfs	Forward Transconductance	37			S	$V_{DS} = 15V, I_D = 12A$
Q_g	Total Gate Charge		34	50		
Q _{gs1}	Pre-Vth Gate-to-Source Charge		9.1			$V_{DS} = 15V$
Q _{gs2}	Post-Vth Gate-to-Source Charge		2.5		nC	$V_{GS} = 4.5V$
Q_{gd}	Gate-to-Drain Charge		12			I _D = 12A
Q _{godr}	Gate Charge Overdrive		10			See Fig. 16
Q _{sw}	Switch Charge (Q _{gs2} + Q _{gd})		15			
Q _{oss}	Output Charge		21		nC	$V_{DS} = 15V, V_{GS} = 0V$
t _{d(on)}	Turn-On Delay Time		25			$V_{DD} = 15V, V_{GS} = 4.5V$
t _r	Rise Time		42			I _D = 12A
t _{d(off)}	Turn-Off Delay Time		34		ns	Clamped Inductive Load
t _f	Fall Time	_	19			
C _{iss}	Input Capacitance		4380			$V_{GS} = 0V$
Coss	Output Capacitance		940		рF	$V_{DS} = 15V$
C _{rss}	Reverse Transfer Capacitance		430			f = 1.0MHz

Avalanche Characteristics

	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy ^②		1440	mJ
I _{AR}	Avalanche Current ①		12	Α
E _{AR}	Repetitive Avalanche Energy ①		14	mJ

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			161 ④		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			620		integral reverse
	(Body Diode) ①					p-n junction diode.
V _{SD}	Diode Forward Voltage			1.0	V	$T_J = 25$ °C, $I_S = 12A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		39	59	ns	$T_J = 25$ °C, $I_F = 12A$, $V_{DD} = 15V$
Q _{rr}	Reverse Recovery Charge		36	54	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD				le (turn-on is dominated by LS+LD)

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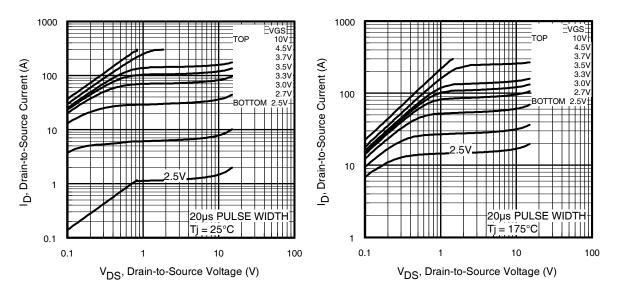


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics

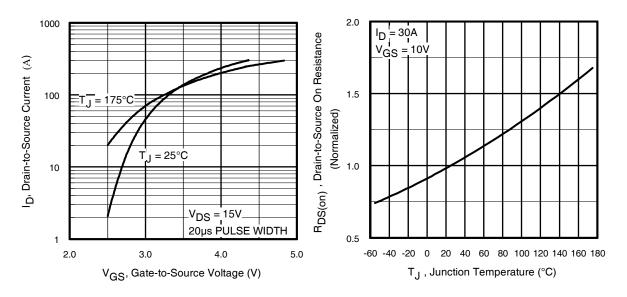


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance vs. Temperature

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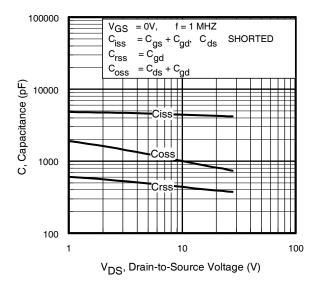


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

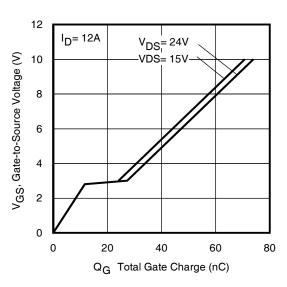


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

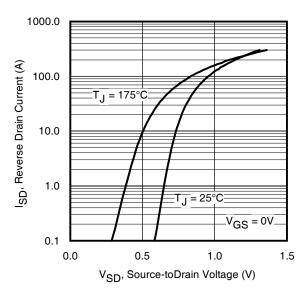


Fig 7. Typical Source-Drain Diode Forward Voltage

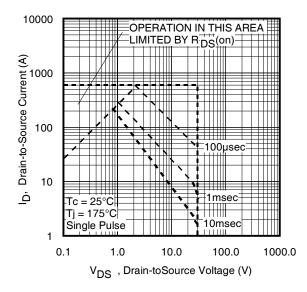
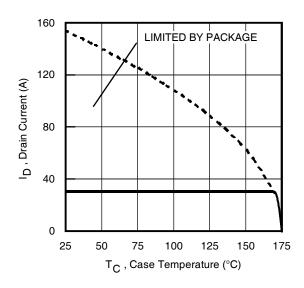


Fig 8. Maximum Safe Operating Area



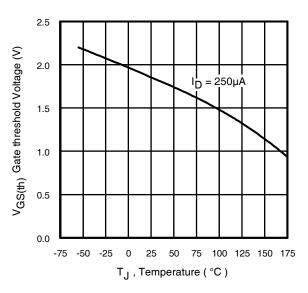


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Threshold Voltage vs. Temperature

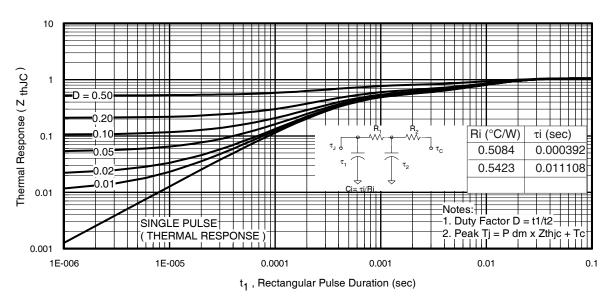


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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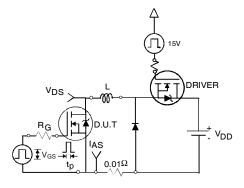


Fig 12a. Unclamped Inductive Test Circuit

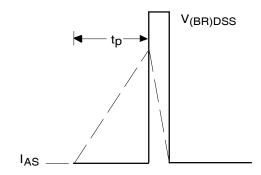


Fig 12b. Unclamped Inductive Waveforms

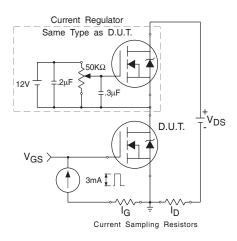


Fig 13. Gate Charge Test Circuit

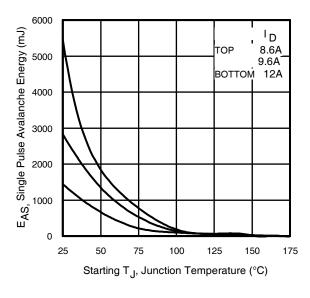


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

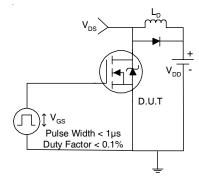


Fig 14a. Switching Time Test Circuit

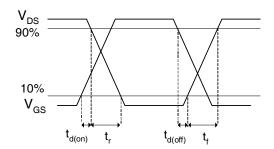


Fig 14b. Switching Time Waveforms www.irf.com

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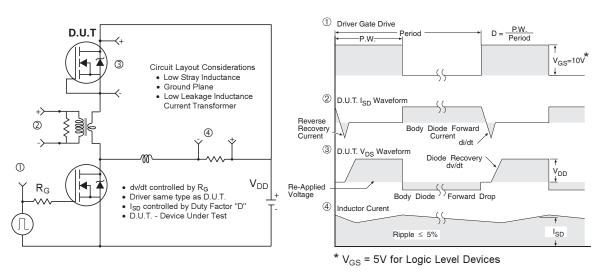


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

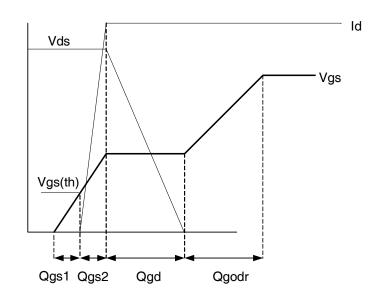


Fig 16. Gate Charge Waveform

Power MOSFET Selection for Non-Isolated DC/DC Converters

Control FET

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the $R_{\text{ds(on)}}$ of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms ${\rm Q_{gs2}}$ and ${\rm Q_{oss}}$ which are new to Power MOSFET data sheets.

 Q_{gs2} is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements, Q_{gs1} and Q_{gs2} , can be seen from Fig 16.

 Q_{gs2} indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to I_{dmax} at which time the drain voltage begins to change. Minimizing Q_{gs2} is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$ is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how $\rm Q_{oss}$ is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's $\rm C_{ds}$ and $\rm C_{dg}$ when multiplied by the power supply input buss voltage.

Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

*dissipated primarily in Q1.

For the synchronous MOSFET Q2, R $_{\text{ds(on)}}$ is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge Q $_{\text{oss}}$ and reverse recovery charge Q $_{\text{rr}}$ both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and $V_{\rm in}$. As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of $Q_{\rm gd}/Q_{\rm gs1}$ must be minimized to reduce the potential for Cdv/dt turn on.

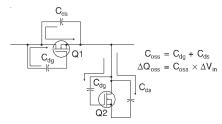
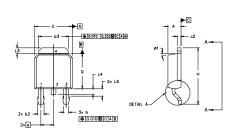


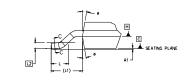
Figure A: Qoss Characteristic

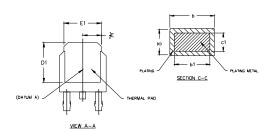
International IOR Rectifier

IRLR/U7843PbF

D-Pak (TO-252AA) Package Outline







DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.

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 LEAD DIMENSION OF MARE SHOWN IN HOHES [MILLIMETERS].

 DIMENSION DI AND ET ESTABLISH A WINNIUM MOUNTING SURFACE FOR THERMAL PAD.

 SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 [0.127] AND

 .010 [0.2540 FROM THE LEAD TIP.

 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED

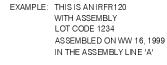
 .005 (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST

 EXTREMES OF THE PLASTIC BODY,

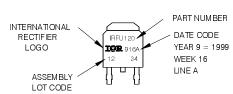
 OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

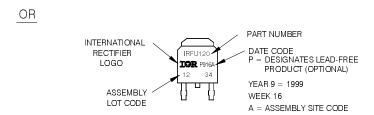
						i
		DIMEN	SIONS			
SYMBOL	SYMBOL MILLIMETERS		INCHES			
	MIN.	WAX.	MIN.	WAX.	NOTES	
A	2.18	2.39	.086	.094		
A1		0.13		.005		
b	0.64	0.89	.025	.035	5	LEAD ASSIGNMENTS
ь1	0.64	0,79	.025	0.031	5	
b2	0.76	1.14	.030	.045		HEXFET
b3	4.95	5.46	.195	.215		
С	0.46	0.61	.018	.024	5	1 GATE
c1	0.41	0,56	.016	.022	5	2 DRAIN
c2	.046	0.89	.018	.035	5	3 SOURCE
D	5,97	6,22	.235	.245	6	4 DRAIN
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	6	IGBTs, CoPACK
E1	4.32	-	.170		4	100135 001 7101
e	2.	29	.090	BSC	ĺ	1 GATE
н	9,40	10,41	.370	.410		2 COLLECTOR
L	1.40	1.78	.055	.070		3 EMITTER
LÍ	2.74	REF	.108	REF.		4 COLLECTOR
L2	0.051	BSC	.020	BSC	1	
L3	0.89	1.27	.035	.050		
L4		1.02		.040		
L5	1,14	1,52	.045	.060	3	
4	0.	10"	0.	10*		
Ø 1	0.	15"	0"	15*		

D-Pak (TO-252AA) Part Marking Information



Note: 'P' in assembly line position indicates 'Lead-Free'



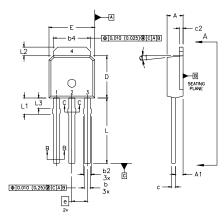


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/ www.irf.com

International IOR Rectifier

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



NO	TFS:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
- DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.

 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

 DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED

 0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST

 EXTREMES OF THE PLASTIC BODY.
- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- LEAD DIMENSION UNCONTROLLED IN L3.

DIMENSION 61, 63 APPLY TO BASE METAL ONLY.
OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA.

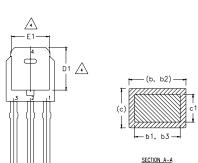
DIMENSIONS

8	CONTROLLING	DIMENSION	:	INCHES.

LEAD ASSIGNMENTS

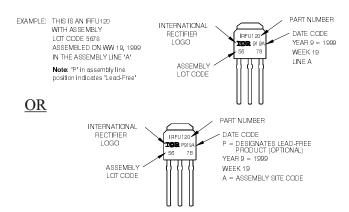
HEXFET

- 1.- GATE
- 2.- DRAIN 3.- SOURCE



SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX,	MIN.	MAX.	NOTES
A	2,18	2.39	0.086	,094	
A1	0.89	1,14	0.035	0.045	
ь	0.64	0.89	0.025	0.035	
ь1	0.64	0,79	0,025	0,031	4
b2	0.76	1,14	0.030	0.045	
b3	0.76	1,04	0.030	0.041	
b4	5.00	5.46	0,195	0.215	4
c	0.46	0.61	0.018	0.024	
c1	0.41	0.56	0.016	0.022	
c2	.046	0.86	0.018	0.035	
D	5,97	6,22	0,235	0,245	3, 4
D1	5.21	-	0.205	-	4
E	6.35	6.73	0.250	0.265	3, 4
E1	4,32	-	0,170	-	4
e	2.	29	0,090	BSC	
L	8.89	9.60	0.350	0.380	
L1	1,91	2.29	0.075	0.090	
L2	0.89	1,27	0,035	0,050	4
L3	1,14	1.52	0.045	0.060	5
ø1	o	15*	0.	15*	
		1	1	1	I

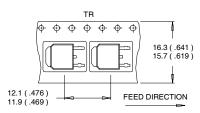
I-Pak (TO-251AA) Part Marking Information

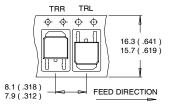


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

D-Pak (TO-252AA) Tape & Reel Information

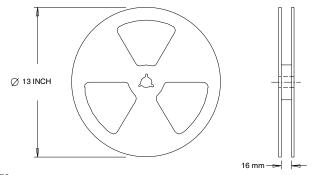
Dimensions are shown in millimeters (inches)





NOTES

- CONTROLLING DIMENSION : MILLIMETER.
 ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:
1. OUTLINE CONFORMS TO EIA-481.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25$ °C, L = 20mH, $R_G = 25\Omega$, $I_{AS} = 12A$.
- ③ Pulse width \leq 400 μ s; duty cycle \leq 2%.
- 4 Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 30A.
- ⑤ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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